## Notice of References Cited Application/Control No. 10/517,105 Examiner TAN X. DINH Applicant(s)/Patent Under Reexamination VERSCHUREN, COEN ADRIANU Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,385,141 b1	05-2002	Tani et al.	369/13.54
*	В	US-7,027,365 b2	04-2006	Verschuren et al.	369/13.09
	O	US-			
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## FOREIGN PATENT DOCUMENTS

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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.